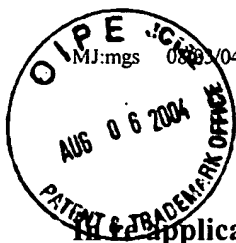


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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of: Doerr et al.

Application No. 10/801,481

Filed: March 15, 2004

Confirmation No. 1207

For: LINEAR OPTICAL SAMPLING
METHODS AND APPARATUS

Examiner: --

Art Unit: 2633

Attorney Reference No. 1505-67922-01

CERTIFICATE OF MAILING

I hereby certify that this paper and the documents referred to as being attached or enclosed herewith are being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: COMMISSIONER FOR PATENTS, P.O. BOX 1450, ALEXANDRIA, VA 22313-1450 on the date shown below.

Attorney
for Applicant(s)

Date Mailed August 3, 2004

**INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. § 1.97(b)(3)**

COMMISSIONER FOR PATENTS
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Listed on the accompanying form PTO-1449 and enclosed herewith are several English-language documents. Applicants respectfully request that these documents be listed as references cited on the issued patent.

If the present application was filed after June 30, 2003, copies of United States patents and United States published patent applications do not have to be provided to the Patent Office. This requirement of 37 C.F.R. § 1.98(a)(2)(i) has been waived by the United States Patent and Trademark Office pursuant to the Official Gazette Notice on August 5, 2003 (1276 OG 55). Applicants will provide copies of such patents upon request.

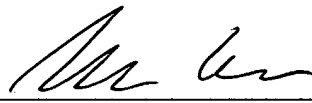
Applicants filed this Information Disclosure Statement ("IDS") before the mailing date of a first Office action on the merits. As a result, no fee should be required to file this IDS. However, if the Patent Office determines that a fee is required for Applicants to file this IDS,

please charge any such fees, or credit overpayment, to Deposit Account No. 02-4550. A **duplicate** copy of this Information Disclosure Statement is enclosed.

The filing of this IDS shall not be construed to be an admission that the information cited in the statement is, or is considered to be, prior art or otherwise material to patentability as defined in 37 C.F.R. §1.56.

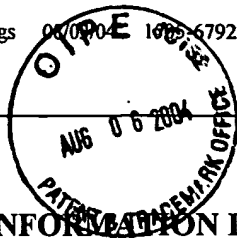
Respectfully submitted,

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Attorney Docket Number	1505-67922-01
Application Number	10/801,481
Filing Date	March 15, 2004
First Named Inventor	Kilper
Art Unit	2633
Examiner Name	Unknown

Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS
		Y. Lai et al., "Characteristic functions and quantum measurement of optical observables," Quantum Opt. 1:99-115 (1989).
		C. Dorrer et al., "High-sensitivity high-resolution sampling using linear optics and waveguide optical hybrid," OFC 2004 (PDP18), Los Angeles, February 22-27, 2004.
		N.G. Walker et al., "Multiport homodyne detection near the quantum noise limit," Optical and Quantum Electronics 18:355-363 (September 1986).
		C. Dorrer et al., "Linear optical sampling," Photon. Tech. Lett. 15:1746-1748 (2003).
		M. Dinu et al., "Amplitude sensitivity limits of optical sampling for optical performance monitoring," J. Opt. Netw. 1:237-248 (July 2002).
		I. Kim et al., "Requirements for the sampling source in coherent linear sampling," Optics Express 12:2723-2739 (June 14, 2004).

EXAMINER SIGNATURE:	DATE CONSIDERED:
<p>* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	